

MOSFET

Metal Oxide Semiconductor Field Effect Transistor

Bare Die

OptiMOS™3 Power MOS Transistor Chip IPC020N10L3

Data Sheet

Rev. 2.5 Final



IPC020N10L3

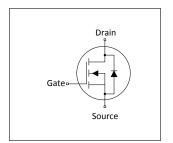
1 Description

- N-channel enhancement mode
- For dynamic characterization refer to the datasheet of BSZ440N10LS3 G
- AQL 0.65 for visual inspection according to failure catalogue
- Electrostatic Discharge Sensitive Device according to MIL-STD 883C
- Die bond: soldered or glued
- Backside metallization: NiV system
- Frontside metallization: AlCu system
- Passivation: nitride (only on edge structure)



<u> </u>					
Parameter	Value	Unit			
V _{(BR)DSS}	100	V			
R _{DS(on)}	441)	mΩ			
Die size	2.1 x 0.96	mm ²			
Thickness	220	μm			











Type / Ordering Code	Package	Marking	Related Links
IPC020N10L3	Chip	not defined	-

2 Electrical Characteristics on Wafer Level

at $T_i = 25$ °C, unless otherwise specified

Table 2

Danier of the	Symbol		Values		1114	
Parameter		Min.	Тур.	Max.	Unit	Note / Test Condition
Drain-source breakdown voltage	V _{(BR)DSS}	100	-	-	V	$V_{\rm GS}$ =0 V , $I_{\rm D}$ =1 mA
Gate threshold voltage	$V_{\rm GS(th)}$	1.1	1.7	2.1	V	$V_{\rm DS}=V_{\rm GS},\ I_{\rm D}=12\ \mu {\rm A}$
Zero gate voltage drain current	I _{DSS}	-	0.1	1	μΑ	V _{GS} =0 V ,V _{DS} =100 V
Gate-source leakage current	I _{GSS}	-	1	100	nA	V _{GS} =20 V ,V _{DS} =0 V
Drain-source on- resistance	R _{DS(on)}	-	42 ²⁾	100 ³⁾	mΩ	V _{GS} =4.5 V ,I _D =2.0 A
Reverse diode forward on-voltage	V _{SD}	-	1.0	1.2	V	V _{GS} =0 V ,I _F =1 A
Avalanche energy, single pulse	E AS	-	18 ⁴⁾	-	mJ	I_D =12 A, R_{GS} =25 Ω

 $^{^{1)}}$ packaged in a S308 (see ref. product). Maximum $R_{DS(on)}$ at V_{GS} =10V

²⁾ typical bare die $R_{\rm DS(on)}$; $V_{\rm GS}$ = 4.5 V ³⁾ limited by wafer test-equipment

⁴⁾ Wafer tested.



3 Package Outlines

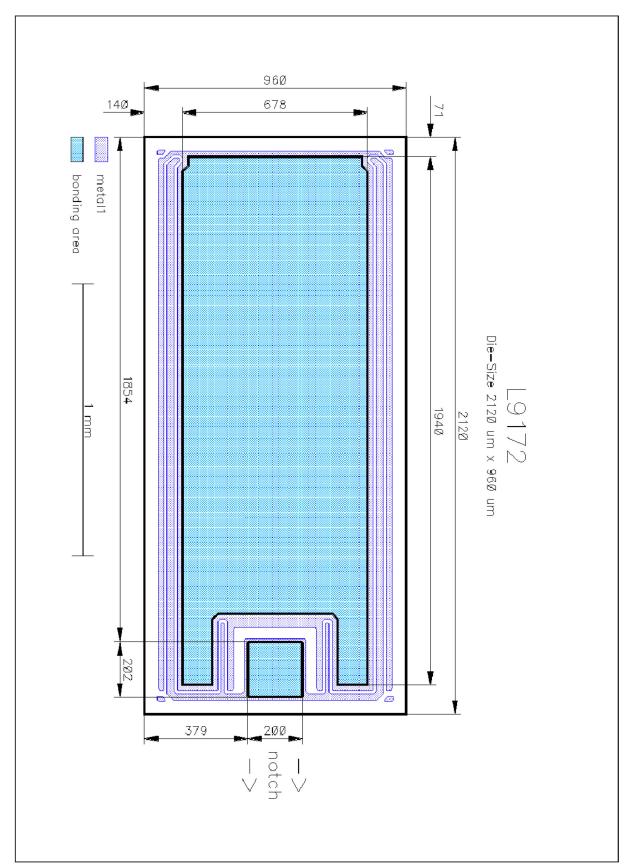


Figure 1 Outline Chip, dimensions in µm



OptiMOS™3 Power MOS Transistor Chip

IPC020N10L3

Revision History

IPC020N10L3

Revision: 2014-07-23, Rev. 2.5

Previous Revision

Revision	Date	Subjects (major changes since last revision)		
2.5	2014-07-23	Release Final Version		

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